

**April 2015** 

# **FDB110N15A**

# N-Channel PowerTrench<sup>®</sup> MOSFET 150 V, 92 A, 11 m $\Omega$

#### **Features**

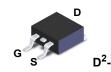
- $R_{DS(on)}$  = 9.25 m $\Omega$  (Typ.) @  $V_{GS}$  = 10 V,  $I_D$  = 92 A
- · Fast Switching Speed
- · Low Gate Charge
- High Performance Trench Technology for Extremely Low  $R_{DS(on)}$
- · High Power and Current Handling Capability
- RoHS Compliant

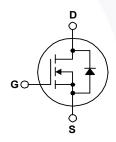
## Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advance PowerTrench® process that has been tailored to minimize the on-state resistance while maintaining superior switching performance.

## **Applications**

- Synchronous Rectification for ATX / Server / Telecom PSU
- · Battery Protection Circuit
- · Motor drives and Uninterruptible Power Supplies
- · Micro Solar Inverter





## **Absolute Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted.

Symbol		Parameter		FDB110N15A	Unit
$V_{DSS}$	Drain to Source Voltage			150	V
V	Cata ta Cauraa Valtaga	- DC		±20	V
$V_{GSS}$	Gate to Source Voltage	- AC	(f > 1 Hz)	±30	V
I <sub>D</sub>	Drain Current	- Continuous (T <sub>C</sub> = 25°C)		92	A
	Drain Current	- Continuous (T <sub>C</sub> = 100°C)		65	A
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	369	Α
E <sub>AS</sub>	Single Pulsed Avalanche E	nergy	(Note 2)	365	mJ
dv/dt	Peak Diode Recovery dv/d		(Note 3)	6	V/ns
D	Dower Dissination	(T <sub>C</sub> = 25°C)		234	W
$P_{D}$	Power Dissipation - Derate Above 25°C			1.56	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Ten	Operating and Storage Temperature Range			°C
T <sub>L</sub>	Maximum Lead Temperatu	re for Soldering, 1/8" from Case for 5	Seconds	300	°C

#### **Thermal Characteristics**

Symbol	Parameter	FDB110N15A	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.64	°C/W
$R_{\theta JA}$			30/00

# **Package Marking and Ordering Information**

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FDB110N15A	FDB110N15A	D <sup>2</sup> -PAK	Tape and Reel	330 mm	24 mm	800 units

## **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	150	-	-	V
ΔBV <sub>DSS</sub> / ΔΤ <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25°C	-	0.09	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 120 V, V <sub>GS</sub> = 0 V	-	-	1	μА
		$V_{DS} = 120 \text{ V}, T_{C} = 150^{\circ}\text{C}$	-	-	500	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V	-	-	±100	nA

#### On Characteristics

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2.0	-	4.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 92 A	-	9.25	11.0	mΩ
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 92 A	-	118	-	S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V - 75 V V - 0 V	-	3390	4510	pF
Coss	Output Capacitance	$V_{DS} = 75 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1  MHz	-	334	445	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1/11/12	-\	14	-	pF
C <sub>oss</sub> (er)	Engry Releted Output Capacitance	V <sub>DS</sub> = 75 V, I <sub>D</sub> = 92 A	-	583	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		- \	47	61	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{GS} = 10 \text{ V}, V_{DS} = 75 \text{ V},$	-	16	-	nC
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau	I <sub>D</sub> = 92 A	-	7.9	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	(Note	4) -	9.7	-	nC

## **Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time			- /	25	60	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 75 \text{ V}, I_{D} = 92 \text{ A},$		- /	26	62	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = 10 V, $R_{G}$ = 4.7 $\Omega$		-/	46	102	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4)	-	14	38	ns
ESR	Equivalent Series Resistance (G-S)	f = 1 MHz		/ -	2.5	-	Ω

#### **Drain-Source Diode Characteristics**

Is	Maximum Continuous Drain to Source Diode	Maximum Continuous Drain to Source Diode Forward Current		-	92	Α
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current		-	-	369	Α
$V_{SD}$	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 92 A		-	-	1.25	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 92 A, V <sub>DD</sub> = 75 V,	-	89	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	255	-	nC

#### Notes

- 1. Repetitive rating: pulse width-limited by maximum junction temperature.
- 2. L = 3 mH, I<sub>AS</sub> = 15.6 A, R<sub>G</sub> = 25  $\Omega$ , starting T<sub>J</sub> = 25°C.
- 3.  $I_{SD} \le 92$  A, di/dt  $\le 200$  A/ $\mu$ s,  $V_{DD} \le BV_{DSS}$ , starting  $T_J = 25^{\circ}C$ .
- Essentially independent of operating temperature typical characteristics.

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

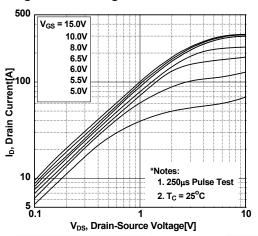


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

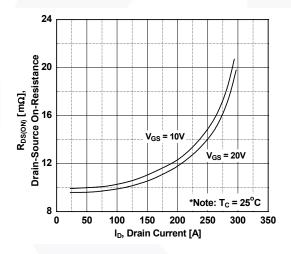


Figure 5. Capacitance Characteristics

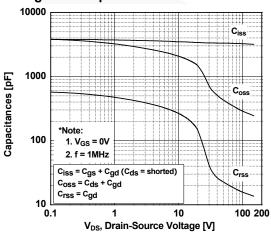


Figure 2. Transfer Characteristics

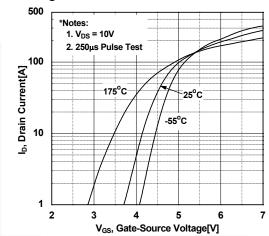


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

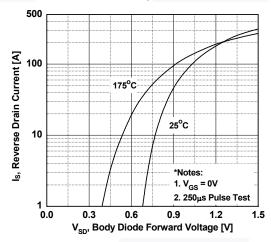
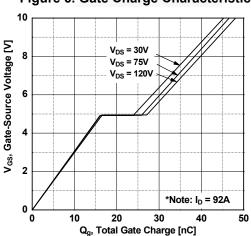


Figure 6. Gate Charge Characteristics



## **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

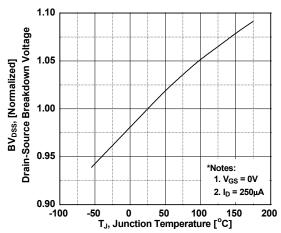


Figure 9. Maximum Safe Operating Area

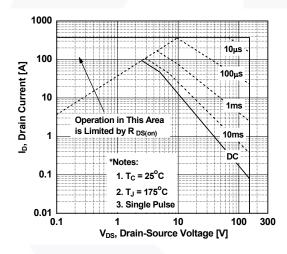


Figure 11. Eoss vs. Drain to Source Voltage

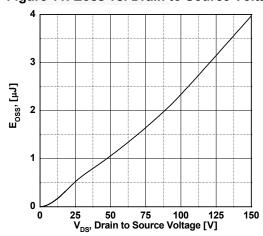


Figure 8. On-Resistance Variation vs. Temperature

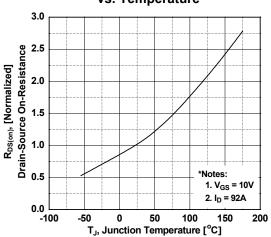
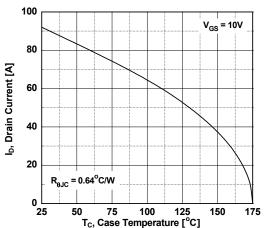
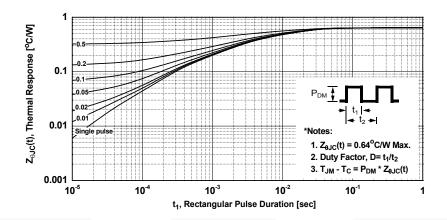


Figure 10. Maximum Drain Current vs. Case Temperature



## **Typical Performance Characteristics** (Continued)

**Figure 12. Transient Thermal Response Curve** 



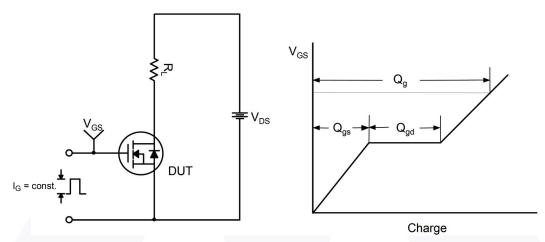


Figure 13. Gate Charge Test Circuit & Waveform

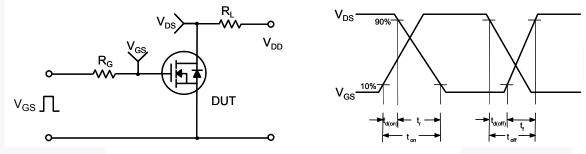


Figure 14. Resistive Switching Test Circuit & Waveforms

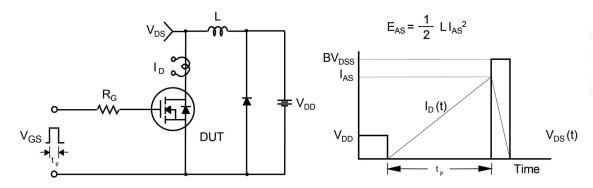


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

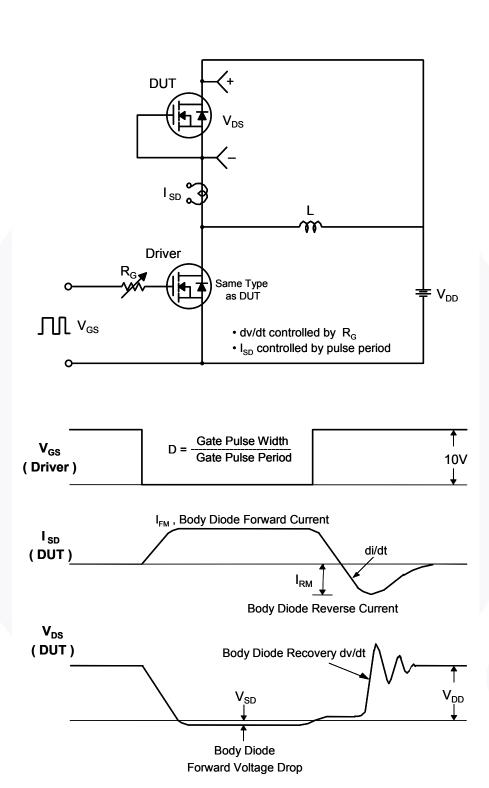
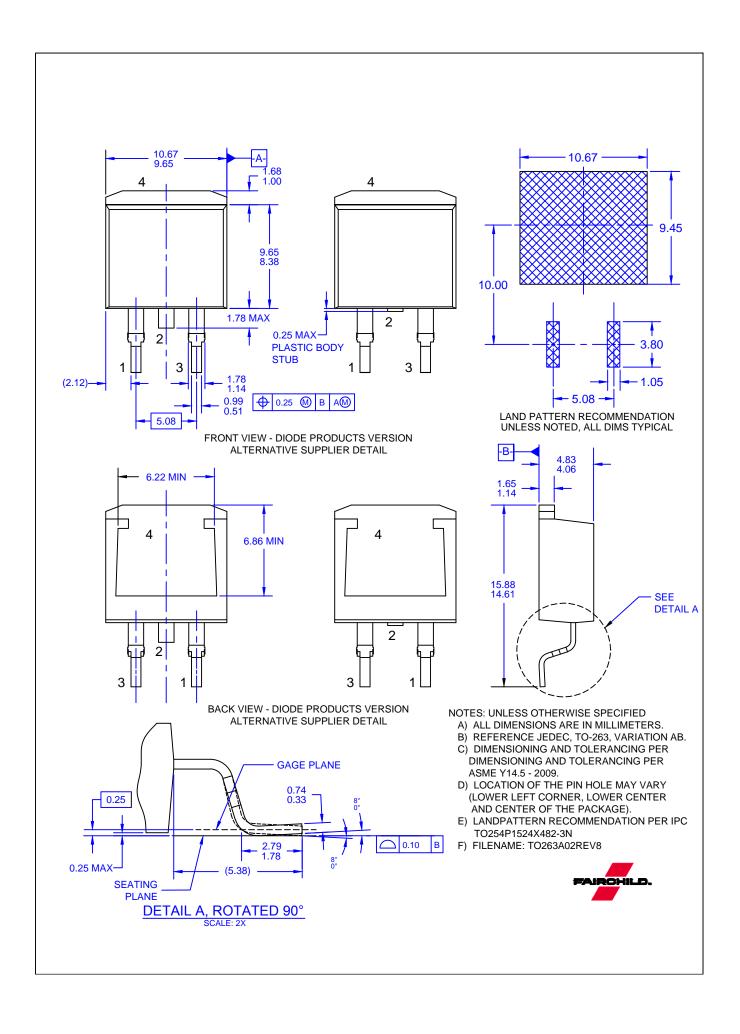


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms



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